Special Issue

Machine Learning and Deep Learning-Based Fault Detection and Diagnosis

Message from the Guest Editors

Modern systems tend to be more complicated than ever before, facilitated by novel design concepts and advancements in new technologies such as sensing, materials, communication, and systems (or functions) integrity. Fault detection and diagnosis are the core of healthy state awareness and prediction, as well as fault prevention. Fault detection and diagnosis of modern systems, however, are difficult to implement owing to (i) it being a coupling subject involving performance analysis, sensor placement and communication, data collection and analysis, as well as benefits evaluation and decision-making; and (ii) it requiring a comprehensive and deep understanding of the working states of complicated systems and their interactive mechanisms with variable (even unpredicted, for some cases) environmental factors. Machine learning and deep learning have emerged and represent promising ways of solving detection and diagnosis problems of modern systems. These novel tools are subverting traditional model-based concepts.

Guest Editors

Prof. Dr. Hong-Zhong Huang Center for System Reliability and Safety, University of Electronic Science and Technology of China, Chengdu 611731, China

Dr. He Li

Centre for Marine Technology and Ocean Engineering (CENTEC) Instituto Superior Técnico, Universidade de Lisboa, 1049-001 Lisbon, Portugal

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As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo Dipartimento di Fisica, Politecnico di Milano, Piazza L. da Vinci 32, 20133 Milano, Italy

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